

Test Clip Product Matrix

Lead Count/ Plating	* Thru-Hole				Surface Mount					Thru-Hole Test Clip
	Standard Model Part Numbers (with Nail Heads)		Connector-Compatible Part Numbers (with Headless Heads)		Connector-Compatible Part Numbers (with Headless Heads)					Surface Mount Test Clips
	DIP .300 Wide	DIP .600 Wide	DIP .300 Wide	DIP .600 Wide	SOIC .150 Body	SOIC .300 Body	SOJ .300 Body	LCC .050	PLCC .050	Types of Computer Chips
8 Alloy Gold	923695 923743-08		923690-08 923739-08		923650-08 923655-08					DIP
14 Alloy Gold	923698 923743-14		923690-14 923739-14		923650-14 923655-14					
16 Alloy Gold	923700 923743-16	923702 923743-16LSI	923690-16 923739-16	923690-16LSI 923739-16LSI	923650-16 923655-16	923660-16 923665-16				SOIC
18 Alloy Gold	923703 923743-18		923690-18 923739-18			923660-18 923665-18				
20 Alloy Gold	923704 923743-20		923690-20 923739-20			923660-20 923665-20	923660-20 923665-20	923680-20 923685-20	923670-20 923675-20	
22 Alloy Gold	923706 923742-22	923705 923743-22	923689-22 923738-22	923690-22 923739-22						
24 Alloy Gold	923715 923742-24	923714 923743-24	923689-24 923738-24	923690-24 923739-24		923660-24 923665-24	923660-24 923665-24			
28 Alloy Gold	923717 923742-28	923718 923743-28	923689-28 923738-28	923690-28 923739-28		923660-28 923665-28	923660-28 923665-28	923680-28 923685-28	923670-28 923675-28	
32 Alloy Gold		923719 923743-32		923690-32 923739-32						
36 Alloy Gold		923720 923743-36		923690-36 923739-36						
40 Alloy Gold		923722 923743-40		923690-40 923739-40						
44 Alloy Gold								923680-44 923685-44	923670-44 923675-44	
48 Alloy Gold		923724 923743-48		923690-48 923739-48						
52 Alloy Gold								923680-52 923685-52	923670-52 923675-52	
64 Alloy Gold		†923726 †923743-64		†923690-64 †923739-64						
68 Alloy Gold								923680-68 923685-68	923670-68 923675-68	
84 Alloy Gold								923680-84 923685-84	923670-84 923675-84	

* For Knife Edge Test Clip use 927 – for all through-hole connector compatible clips. (Available with gold plated leads only, without nailhead.)
 † .900 Wide

3M Logical Connection Product Matrix

3M Logical Connection		DIP (.100" Spacing)				
		No. of Contacts	Pin #1 (L)		Pin #1 (R)	
Remote-end Termination Connector	Description		Cable Assembly Only (w/o test clip) Part No.	#1 Pin Pos.	Logical Connection (w/test clip) Part No.	#1 Pin Pos.
	Open end	16	922490-16	L	923880-16	R
		20	922490-20	L	923880-20	R
		24	922490-24	L	923880-24	R
		28	922490-28	L	923880-28	R
		40	922490-40	R	923930-40	L
		48	922490-48	R	923930-48	L
	DIP Connector - mates with standard 16, 20, 24, 28 and 40 pin DIP Sockets.	16	922594-16	R	923884-16	R
		20	922594-20	R	923884-20	R
		24	922594-24	R	923884-24	R
		28	922594-28	R	923884-28	R
		40	922594-40	R	923884-40	R
	Socket Connector - mates with 2 rows of .025" sq. or dia. pins on .100" centers and shielded receptacles.	16			923881-16	R
		20			923881-20	R
		26*			923881-24	R
		30*			923881-28	R
		40			923881-40	L
		50*			923881-48	L
64			923881-64	L		

3M Test Clip Cable Assemblies

Remote test equipment can be easily connected to IC circuitry when the performance proven 3M IC Test Clip is combined with 3M's complete, tested, ready-to-use cable assembly. This combination, "The Logical Connection," is the ideal connection from a logic analyzer to an IC. On one end, socket connectors attach to the pins of a connector-compatible model test clip. On the other end, 3M provides either an open ended cable or a termination method suited to your application. Utilizing "Logical Connection" cable assemblies provide valuable features and reliability.

- Connectors ensure optimum electrical integrity and strain relief.
- Probe holes in the back of all connectors allow easy access to individual lines.
- Cable loops between connectors allow free actuation of the test clip for clearance over all package styles.

* On 26 position connectors, positions #25 and #26 are unused. On 30 position connectors, positions #29 and #30 are unused. On 50 position connectors, positions #49 and #50 are unused.

What makes 3M products unique

Surface Mount Test Clips

3M Surface Mount Integrated Circuit Test Clips provide a downsized series made for today's smaller components and higher densities. Now hard-to-access Surface Mount ICs can be connected to test probes and logical assemblies quickly and easily without the risk of shorting out clips or damaging other board components.

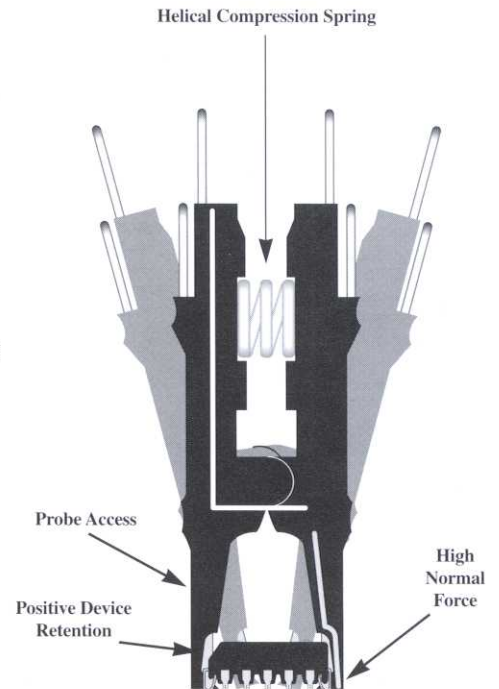
3M Surface Mount test clips are available in different pin sizes to accommodate a wide range of requirements.

Industry standard .025" square contact pins on .050" centers are staggered to permit easy attachment of IDC socket connectors or wire wrappings and help prevent shorting of adjacent probes. With these smaller test clips, you can stack SOIC's as close as .050" end-to-end, and PLCC's on .200" centers. In addition, the 3M clips allow safe, accurate and convenient testing of Plastic Leaded (PLCC) and Leadless Ceramic (LCC) Chip Carrier style integrated circuits. The unique action-wedge design of the test clip allows all four of its sides to open simultaneously for a one step, secure attachment to the PLCC being tested.

General features

- Test devices down to .050" center to center lead spacing.
- All four sides of test clip open simultaneously for one-step attachment to PLCC being tested.
- Stays securely clamped to PLCC.
- Helical compression springs and insulating contact combs ensure contact integrity during testing.
- Probe access points are immediately visible for fast and safe individual lead testing.
- Staggered contact rows on .100" centers facilitate probe attachment and help prevent accidental shorting of adjacent probes.
- Industry standard .025" square contact pins on the .100" centers easily accept single row socket connectors.
- Because of positive attachment to device, test clip will not "fall off" when board is vertical and test probes are hung off the pins.

- Wiping action and high normal force combine to provide excellent electrical contact.
- Available in gold plated or alloy 770 leads.



Unique Design Features

Of the many design features that make the 3M Test Clip "a breed apart," the care taken in contact design is but one of them. Each contact has been designed for a specific device to insure:

- High normal force
- Excellent electrical contact
- Long-term performance

